

AMENDMENTS TO THE CLAIMS

1. (Previously Presented) A method of evaluating a piezoelectric field comprising:
measuring a first absorption spectrum of a sample by irradiating the sample with infrared light at a first angle;
measuring a second absorption spectrum of the sample by irradiating the sample with the infrared light at a second angle, different from the first angle;
specifying a peak position of an absorption band having incident-angle dependent intensity based on the first absorption spectrum and the second absorption spectrum; and
obtaining the piezoelectric field strength using a relationship between the piezoelectric field and electron energy level corresponding to the peak position of the absorption band.
2. (Previously Presented) The method according to claim 1, wherein the piezoelectric field is an electric field induced by a lattice-mismatch strain in a semiconductor heterojunction of the sample.
3. (Previously Presented) The method according to claim 1, wherein measuring the first absorption spectrum includes:
measuring, in advance, a reference spectrum by changing wavelength of the infrared light within a predetermined range;
irradiating the sample with the infrared light and changing the wavelength of the infrared light within the predetermined range; and
calculating the first absorption spectrum based on the infrared light which is transmitted through the sample.
4. (Previously Presented) The method according to claim 1, wherein measuring the second absorption spectrum includes irradiating the sample with the infrared light at the second angle by rotating a turntable on which the sample is placed.
5. (Currently Amended) The method according to claim 4, wherein measuring the second absorption spectrum includes:
detecting deviation of an optical axis of the infrared light which ~~is~~ irradiates the sample and is transmitted through the sample;
correcting the deviation of the optical axis; and
calculating the second absorption spectrum based on the infrared light which is transmitted through the sample.

6. (Previously Presented) A method of evaluating a piezoelectric field comprising:
measuring a first absorption spectrum of a sample by irradiating the sample with
infrared light;

measuring a second absorption spectrum of the sample by irradiating the sample,
while placed on a turntable, with infrared light, and vibrating the turntable with a
predetermined angular frequency;

specifying a peak position of an absorption band having incident-angle dependent
intensity based on the first absorption spectrum and the second absorption spectrum; and

obtaining the piezoelectric field strength using a relationship between the
piezoelectric field and electron energy level corresponding to the peak position.